## Date Created : 2007/12/03 Date Issued On : 2008/01/22 PCN# : Q4074901

## DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor** within 30 days of receipt of this notification.

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

<u>Technical Contact:</u> Name: SONG, HEEYUNG E-mail: HEEYUNG.SONG@fairchildsemi.com Phone: 82-32-680-1216

<u>PCN Originator:</u> Name: SONG, HEEYUNG E-mail: HEEYUNG.SONG@fairchildsemi.com Phone: 82-32-680-1216

Implementation of change: Expected 1st Device Shipment Date: 2008/04/06

Earliest Year/Work Week of Changed Product: 0815

Change Type Description: Test Location

Description of Change (From): Assembly & TEST: Fine Silicon Power Networks(FineSPN)

Description of Change (To): Assembly: Fine Silicon Power Networks(FineSPN) Test: DB Power Tech Inc. It's also certified for ISO9001 and ISO14001 certificated.

Reason for Change : Outsourcing of Final test. There are no changes to equipment and system.

Qual/REL Plan Numbers : Q20070533

Qualification :

This change doesn't require Reliability test.

## **Results/Discussion**

Test: (Bake)				
Lot	Device	24-HOURS	Failure Code	
Q20070533AABAKE	FMG2G75US60	0/11		

Product Id Description : All IGBT MODULE devices packaged with 25PM-AA, 7PM-GA, 7PM-HA, 7PM-IA. The products affected by this change are listed below in the "Affected FSIDs" section.

Affected FSIDs :

FMG2G100US60	FMG2G150US60	FMG2G150US60E	
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FMG2G200US60	FMG2G300LS60E	FMG2G300US60
FMG2G300US60E	FMG2G400LS60	FMG2G400US60
FMG2G50US60	FMG2G75US60	